

13th "Trento" Workshop on Advanced Silicon Radiation Detectors

Tuesday 20 February 2018

CMOS sensors: : (11:15 - 13:00)

-Conveners: Dominik Dannheim

time	[id] title	presenter
11:15	[77] Radiation-hard passive CMOS-sensors	POHL, David-Leon
11:30	[85] Recent developments on monolithic CMOS pixel sensors in TowerJazz 180nm technology	RIEGEL, Christian
11:45	[80] Performance of the H35DEMO chip monolithic matrices before and after irradiation	TERZO, Stefano
12:00	[78] Characterization of H35 HV-CMOS Sensors before and after Proton Irradiation	SULTAN, D M S
12:15	[79] Depleted monolithic CMOS pixels using column drain readout for the ATLAS Inner Tracker	WANG, Tianyang
12:30	[82] E-TCT characterisation of irradiated backside biased H35DEMO pixel demonstrators	Mr FRANKS, Matthew
12:45	[81] Effect of thinning and backplane processing on charge collection properties of irradiated CMOS	MIKUZ, Marko